

# HISIM: Analytical Performance Modeling and Design Space Exploration of 2.5D/3D Integration for AI Computing

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**Abstract**—Monolithic designs face significant fabrication cost and data movement challenges, especially when executing complex and diverse AI models. Advanced 2.5D/3D packaging promises high bandwidth and connection density to overcome these challenges, yet it also introduces new electro-thermal constraints. This paper develops a suite of analytical performance models to enable efficient benchmarking of a 2.5D/3D heterogeneous system for energy-efficient AI computing. These models encompass various performance metrics related to computing units, network-on-chip, and network-on-package. The results are summarized into a new tool, HISIM, which is  $10^4$ – $10^6$ × faster than state-of-the-art AI benchmark tools. Furthermore, HISIM integrates rapid thermal simulation for the 2.5D/3D system, helping shed light on both the potential and limitations of 2.5D/3D heterogeneous integration on representative AI algorithms. The code of HISIM is available at <https://github.com/mec-UMN/HISIM>.

**Index Terms**—heterogeneous integration, 2.5D/3D, chiplet, in-memory computing, network-on-package, thermal simulation

## I. INTRODUCTION

Artificial intelligence (AI) systems have effectively addressed practical problems across multiple domains. The complexity of state-of-the-art AI models, such as deep neural networks (DNNs), transformers, and graph neural networks (GNNs), grows continuously to enable higher accuracy and capabilities [1], [2]. Existing monolithic integrated circuits

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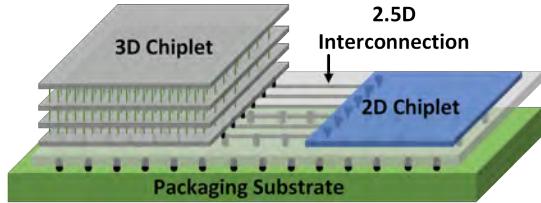


Fig. 1. Architecture overview of a 2.5D/3D heterogeneous system.

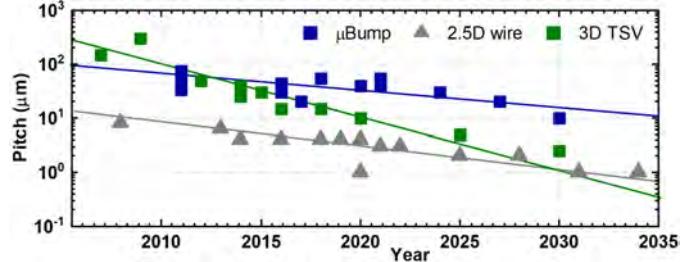


Fig. 2. The scaling trend of various interconnections in 2.5D/3D packaging. Symbols are from references [11]–[26].

(ICs) offer many benefits for AI acceleration with large-scale integration and high performance. However, their scaling trend still lags behind contemporary AI models, particularly on the demand of memory access, on-chip cache capacity, and data movement. For instance, vision transformer (ViT) utilizes over 300 million parameters and 24 layers for image classification [3], [4]. If all the weights were mapped on a 28nm monolithic chip, it could require an area of more than  $3,000\text{mm}^2$  [5]. Designing accelerators for such big AI models poses a tremendous challenge, especially for edge devices.

Due to the limited monolithic area available for processing big AI models, their training and inference require frequent data movement between external memory and processing units, which becomes the dominant factor of energy consumption and latency [6]–[10]. In this context, recent advances in 2.5D/3D packaging provide a promising solution to address the challenges of high bandwidth, low-power data movement, and large-scale integration that are essential for big AI models.

Figure 1 illustrates a heterogeneous architecture that contains multiple chiplets connected via a 2.5D bridge embedded in silicon interposer, glass, or organic substrate, and/or 3D interconnections (such as through-silicon-vias or TSVs). The network-on-package (NoP) enables inter-chiplet communica-

tion with multiple channels, designed to deliver higher bandwidth, lower energy consumption per bit, and lower fabrication costs compared to traditional monolithic designs [27], [28]. Although 2.5D integration is currently available, it requires more physical space compared to 3D integration due to the additional peripheral circuits for inter-chiplet signaling. In contrast, future 3D stacking with TSVs offers more compact integration and denser connections, yet it will face significant thermal and reliability challenges [29]–[31]. Both architectures have a consistent scaling roadmap to reduce the feature size of interconnections, as shown in Figure 2. This trend ensures a continuous improvement in data movement among chiplets.

As the advancement of 2.5D/3D heterogeneous integration (HI) opens enormous opportunities for future big AI computing, the mapping and optimizing target AI algorithms on a HI system present intriguingly complex challenges, attributed to the abundance of design variables involved in this process. These variables include algorithmic structures (such as layers, kernel size, precision, etc.), technology parameters (such as 2.5D, 3D, interconnection, etc.), design choices (such as computing cores, array size, network topology, memory, etc.), and placement and routing schemes. To perform algorithm-hardware co-design in such a vast space, early-stage design space exploration is critical to narrow down the design scope and derive valuable insights at the architecture level. Such exploration requires a 2.5D/3D HI simulator that is *scalable* with essential design variables, *fast* in end-to-end performance prediction, and *accurate* in key performance metrics. This tool can be employed during the initial phase of architectural definition, complementing commercial 2.5D/3D EDA tools that generate physical details in subsequent stages.

This paper presents a benchmark tool, Heterogeneous Integration Simulation with Interconnect Modeling (HISIM). Distinguished from previous simulation tools that contain many technological and circuit details, HISIM focuses on key system-level metrics, such as latency, energy consumption, and data movement. This emphasis achieves a balance between model scalability, accuracy, and efficiency in order to support fast algorithm-hardware co-design. Table I summarizes some recent simulators for chiplet and related network communication. Several simulators target computing units, particularly the latest in-memory computing (IMC) cores, such as NeuroSim [32] and MNSIM [33]. Because these simulators typically use a bottom-up approach, beginning with devices, followed by circuits, and ultimately systems, their simulation speed is usually slow. In addition, there is a need for full consideration of 2.5D/3D network communication among multiple cores. Some other simulators, such as BookSim 2.0 [34] and Ratatoskr [35], provide cycle-accurate simulation and performance evaluation of 2D network-on-chip (NoC) fabrics. With the growing data volume of AI models, it requires a long simulation time to evaluate NoC performance. Our recent tool SIAM [5] integrates 2.5D silicon bridges with IMC units. Yet SIAM is still too slow to explore diverse design configurations. Furthermore, more advanced 3D design issues, such as network-on-package (NoP), thermal analysis, and reliability prediction, must be incorporated for a comprehensive performance evaluation.

To address these challenges of benchmarking 2.5D/3D HI

TABLE I  
COMPARISON OF STATE-OF-THE-ART CHIPLET AND AI SIMULATORS.

Simulator	Computing Unit	Dimension	Thermal Analysis	Simulation Speed
NeuroSim [36]	IMC	2D/3D	Yes	Slow
MNSIM [33]	IMC	2D	No	Slow
BookSim 2.0 [34]	No	2D	No	Slow
Ratatoskr [35]	No	3D	No	Slow
SIAM [5]	IMC	2.5D	No	Slow
<b>HISIM</b>	<b>IMC and others</b>	<b>2.5D/3D</b>	<b>Yes</b>	<b>Fast</b>

systems, HISIM adopts a systematic approach. It considers the hierarchy in both computing and data movement, abstracts the relationship between key design variables and performance metrics into analytical models, and validates the results with simulation and silicon data. The major innovations include:

- *System-level Performance Modeling*: Instead of an extensive stack of models ranging from devices to circuits and to architectures, we aim to construct a set of analytical models that directly connect algorithmic and design decisions with system metrics, such as power, performance, and area (PPA) of various computing chiplets and NoC/NoP. During the model development, each system metric is decomposed into primary design macros, such as a computing array and its peripherals, following the design structure and data flow. Subsequently, the dependence on each macro is calibrated with realistic design databases and process design kits (PDKs).
- *Model Calibration*: To ensure the scalability and accuracy of system-level models, we perform comprehensive validation with various sources, including design synthesis, numerical simulations, published silicon data, and other simulators. By designing and synthesizing diverse chiplet and network configurations, we extract model coefficients and confirm their scalability of design parameters. These results are further verified by published silicon data in the literature, as well as simulations from rudimentary tools. For electrical parasitic modeling of packaging technologies, TCAD simulations are used for model calibration.
- *Thermal Analysis*: Electro-thermal reliability emerges as a critical issue in compact 2.5D/3D integration. The current version of HISIM integrates a coarse-mesh based finite-element method (FEM) to speed up static thermal prediction. Moreover, an even faster method, leveraging graph neural networks, will be adopted by HISIM for further electrical and mechanical reliability analysis.

The outcome of these efforts is HISIM, an analytical model-based tool for fast design exploration of 2.5D/3D HI systems. By inputting the profile of an AI model and its hardware mapping method, HISIM rapidly predicts end-to-end performance, helping shed light on the capabilities and constraints of algorithm-hardware co-design. Initial experiments on representative DNNs, transformers and GNNs demonstrate a speedup of  $10^4$ – $10^6$  × in PPA evaluation compared to previous benchmark tools, while preserving model scalability and accuracy. The code of HISIM is released at <https://github.com/mec-UMN/HISIM>, along with a quick tutorial. The following sections present the technical details of model derivation, validation, and experiments.

## II. BACKGROUND AND RELATED WORK

2.5D/3D heterogeneous integration leverages cutting-edge packaging technologies to integrate various chiplet types into a large-scale system. This section reviews relevant topics that lead to the development of HISIM.

### A. Chiplet-based Heterogeneous Integration

Chiplet-based heterogeneous integration has emerged as a promising solution to tackle the manufacturing and cost challenges of large-scale monolithic chips, where fabrication costs rise exponentially with increased chip area [5], [37]. Moreover, chiplet architectures offer bandwidth and density advantages over clusters of accelerators [2], improving the performance of various applications [38], [39].

Within a chiplet-based system, multiple chiplets are interconnected via special IO protocols or Network-on-Package (NoP), either within a 2.5D substrate or through 3D connections. For example, Advanced Interface Bus (AIB) [40] is a parallel IO interface boasting a bandwidth of 4Gbps/pin, providing high interconnect density in a 2.5D system. A more recent standard for die-to-die serial buses is Universal chiplet interconnect express (UCIE) [41]. Despite their high IO bandwidth, the number of interconnect links is constrained by the length of the shoreline or die edge.

In contrast, 3D chiplet-based architecture provides significantly higher bandwidth and shorter signal distances between chiplets through various methods, such as face-to-back topology with C4 bumps [42], face-to-face topology with microbumps [26], hybrid bonding [43], or 3D stacking with TSVs. Various 3D implementations have been studied, ranging from logic-on-logic to logic-on-memory [44]. In general, both 2.5D and 3D technologies enable the integration of chiplets manufactured at different silicon technology nodes or even different types of materials [36].

As 2.5D/3D HI significantly enhances the scale, density, and potential of system integration, there is an increasing demand for a comprehensive tool for algorithm-hardware co-design. Emerging topics of interest include the management of diverse computing cores, hierarchical data movement from on-chip to chiplet-to-chiplet and 3D connections, thermal implications [45], power delivery, and workload mapping. This tool should seamlessly incorporate the latest packaging technologies for architecture exploration.

### B. In-Memory Computing

To tackle the challenge of extensive memory access during AI computing, in-memory computing has emerged as an advanced accelerator beyond CPUs and GPUs. These accelerators feature a processing element that can be based on either SRAM [46] or non-volatile memory, such as Resistive RRAM (RRAM) [47]. IMC allows for parallel computing of matrix-vector multiplication in analog and digital domains. This operation includes bit-wise multiplication within the memory cell and accumulation along the bit line, achieved through analog resistive/capacitive integration or digital adder trees. For RRAM-based analog IMC, additional peripherals

are required, such as ADC and DAC units, bit shifters for weight bit slicing and sequential inputs [47], and MUXs for sharing ADCs across columns. Previous studies, including our research on SIAM [5], have demonstrated simulations and silicon prototypes of IMCs. They are ready for integration into a HI system alongside other types of AI accelerators and more conventional processing cores.

### C. Performance Benchmark Tools

There are several benchmark tools for monolithic IMC-based DNN inference and network design, as shown in Table I. These tools usually include IMC crossbars connected by point-to-point interconnection for the on-chip network communication [32], [48]. Neurosim 3D [36] implements monolithic 3D integration (M3D), which partitions memory and logic for RRAM-based IMC, and Neurosim 3D+ [48] extends to heterogeneous 3D integration (H3D) of logic-to-memory with TSVs. However, these works lack the incorporation of logic-on-logic stacking and do not include NoC. Booksim [34] is an NoC simulator, offering the flexibility of network topology, routing, and router architectures. [35] conducts PPA analysis for 3D networks at the RTL level. [5] proposes SIAM that combines IMC circuits, NoC, and NoP for a 2.5D chiplet-based system.

These previous works provide important knowledge of devices, circuits and architecture, especially on IMC design. However, they face long simulation times, which are insufficient to manage big AI models in the vast design landscape of 2.5D/3D integration.

## III. HISIM FOR 2.5D/3D SYSTEM ANALYSIS

In contrast to the aforementioned benchmark tools, HISIM introduces a suite of analytical models at the system level to speed up performance prediction, covering logic-on-logic architectures across 2D, 2.5D, and 3D integration. Although HISIM currently emphasizes IMC as the main AI accelerator, we plan to evolve HISIM into an open platform capable of simulating other computing, memory, and communication technologies. The potential users of HISIM include, but are not limited to, architecture research on design space exploration before detailed architecture definition, compiler developers to optimize the mapping strategy, and technology developers to benchmark the impact of 2.5D/3D packaging technology on system design. This section elaborates on the benchmark engines in HISIM. Figure 3 illustrates the structure, input, and output of HISIM. The design synthesis and model calibration in this study are conducted at the 32nm/28nm node. Meanwhile, the models and methods in HISIM are scalable to other process technology nodes and assembly design kits (ADKs).

### A. Overview of HISIM

Figure 3 overviews the proposed HISIM benchmark tool for evaluating the performance of chiplet-based monolithic (2D), 2.5D, and 3D architectures. Users can define the technology and AI algorithms as inputs to HISIM. On the technology aspect, users have the flexibility to select the type of computing

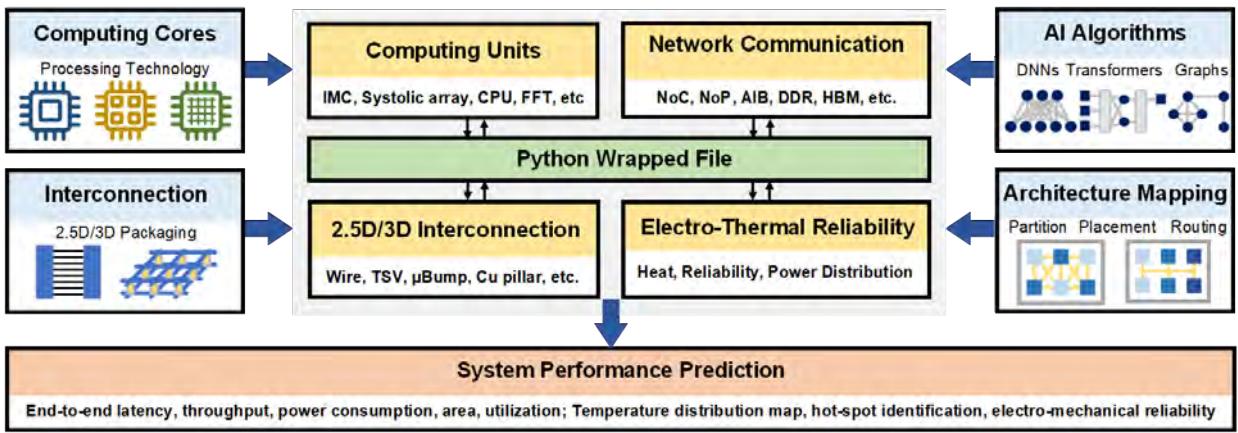


Fig. 3. Overview of HISIM for 2.5D/3D systems. HISIM comprises four engines: computing, interconnection, network and reliability. It integrates inputs from technology, design configuration, AI algorithms and mapping methods to predict system performance metrics, such as PPA and the thermal map.

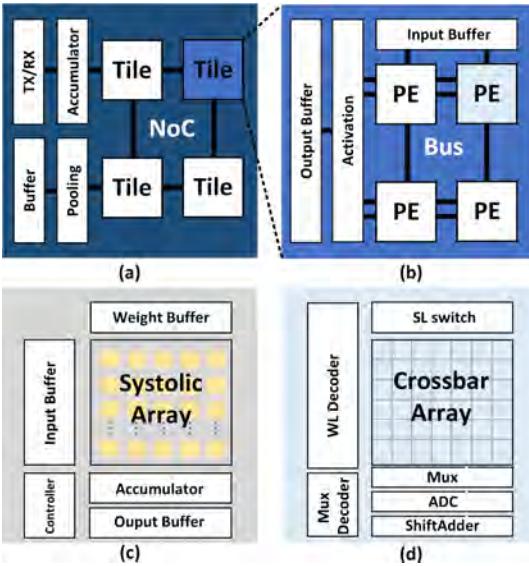


Fig. 4. The hierarchy of the heterogeneous chiplet (a), tile (b), systolic array (c), and IMC PE (d); Users can choose the type of chiplet, tile, and PE in HISIM.

cores, interconnect options (such as 2.5D or 3D), and hardware configurations (such as array size and the number of tiers in 3D stacking). On the algorithm aspect, HISIM supports various DNNs, GNNs, and transformers.

In addition, users need to customize the strategy for workload mapping and data flow, such as algorithm partition, task scheduling, data reuse, routing, placement, etc. Based on user inputs, HISIM generates the specific heterogeneous chiplet-based architecture and analyzes area, power estimation, latency, utilization and energy efficiency. The combination of the HI structure and power density is further used to produce the thermal map.

### B. Computing Cores

Computing cores are vitally important to processing AI tasks. HISIM currently features analytical models for IMC-based computing chiplets using RRAM-based crossbars and systolic arrays which is shown in Figure 4 (c). The methodology will be generalized to digital IMC and other types of processing elements (GPU, CPU, etc.) in the future.

1) *IMC Tiles and Mapping*: Figure 4 (a)(b)(d) presents the design levels within an IMC chiplet, with related input and output parameters defined in Table II. Each chiplet contains multiple tiles,  $N_{tile}$ , and peripherals connected by NoC. An IMC tile comprises several processing elements (PEs) denoted as  $N_{pe}$ , along with the accumulation module responsible for adding partial sums from PEs, input/output buffers for storing activations, and a data bus facilitating data communication within the tile. Additionally, the tile incorporates nonlinear activation modules, such as ReLU, for the activation function of each layer within the neural network. These PEs and macros are interconnected via the databus. This architectural configuration is consistent with other simulators discussed in previous studies [32], [33] and is applicable to other array-based computing cores (such as the systolic array).

The PE is the core computing unit in a chiplet. The PE design depends on the specific processing technology to model. As an example, an analog IMC-based PE has one IMC crossbar along with peripheral circuitry, including drivers, multiplexers, and ADCs. The IMC crossbar performs computations by executing the multiply-and-accumulate (MAC) operation.

In HISIM, rather than limiting users to a fixed compilation method, HISIM aims to support multiple types of compilation approaches, allowing users to optimize their designs as needed. Users can define the partition and mapping strategy for the weights of an AI model onto the IMC crossbar, PE, and tile. In this study, we employ the conventional DNN weight partition

TABLE II  
INPUT PARAMETERS OF IMC CHIPLET MODELS.

Inputs	Level	Description
$In_x, In_y$	AI model	Input size of each layer
$K_x, K_y$		Kernel size of each layer
$F_{in}, F_{out}$		Input channel, output channel
$Q_w, Q_a$		Quantization bit of weights, activation
$S$		Weight sparsity
$st$		Stride of each layer
Pooling		Followed by pooling or not
$N_{tier}$	Chip	Number of chiplets or 3D tiers in the system
$N_{tile}$	Tier	Number of tiles per tier (chiplet)
$N_{pe}$	Tile	Number of PE in Tile
$X_{bar}$	PE	Crossbar size
$C_i$	Mapping	Number of parallel IFM computes
$C_w$	Mapping	Weight duplication factor within a crossbar

and mapping method to map the weights of AI models, as outlined below:

$$total_{xbar} = \left\lceil \frac{Bit_{col}}{X_{bar}} \right\rceil \times \left\lceil \frac{Bit_{row}}{X_{bar}} \right\rceil \quad (1)$$

$$total_{tile} = \frac{total_{pe}}{N_{pe}}; total_{pe} = \frac{total_{xbar}}{N_{xbar}}; \quad (2)$$

$$Bit_{col} = K_x \times K_y \times F_{in}; Bit_{row} = F_{out} \times Q_w \quad (3)$$

2) *Performance Modeling*: The performance of the chiplet component is modeled using the design structure and parameters in Table II as follows:

$$L_{chiplet} = L_{pooling} + L_{accum} + L_{noc} + \sum_i L_{layer_i} \quad (4)$$

$$E_{chiplet} = E_{pooling} + E_{accum} + E_{noc} + \sum_i E_{layer_i} \quad (5)$$

Each layer of an AI model is mapped to a set of crossbars using conventional weight partitioning and mapping method described above. The cumulative performance of crossbars mapped for a layer of the AI algorithm is modeled as follows:

$$L_{layer_i} = L_{max_{xbar}} \frac{N_{act} Q_{act}}{C_i C_w (st^2)} \quad (6)$$

$$E_{layer_i} = E_{max_{xbar}} \frac{N_{act} Q_{act}}{st^2} \frac{2N_W Q_W}{(xbar_x)(xbar_y)st^2} \quad (7)$$

In these equations,  $N_{act}/st^2$  represents the number of convolutional windows, while  $N_W$  denotes the total number of weight parameters. The value of  $N_W$  varies depending on the layer type, whether it is convolution (CONV), fully connected (FC), or depthwise convolution (DW). Assuming a synchronous design, the maximum latency of a layer depends on the crossbar with the highest latency, multiplied by the number of cycles of crossbar computation. The number of cycles, in turn, is influenced by several factors. These factors include the number of convolution windows, serial computation of input bits, parallel computation of input feature map (IFM), and weight duplication, which is a technique employed for Depthwise convolution [49].

The energy model is derived from its dependency on the sum of the multiplication of factors, such as the maximum energy of the crossbars, the crossbar utilization, and the number of times each crossbar is computed. We then derive the above equation by summing the crossbar utilization, which depends on the cumulative utilization of memory cells. This equation is obtained assuming all the crossbars inside a layer are computed the same number of times, similar to the mapping specified in [49], and the input sparsity is 0%. Additionally, a factor of 2 is considered for signed weights, assuming a double row configuration as detailed in [49].

The maximum latency of a crossbar is influenced by the crossbar mapped with maximum utilization, which further relies on the mapping and the number of output feature maps (OFMs), typically a multiple of the ADC sharing factor for neural networks. Moreover, the maximum energy of a crossbar is influenced by factors such as the current of each cell, read voltage, the total number of cells in the crossbar, and activity

TABLE III  
COMPARISON WITH REFERENCE RRAM BASED SYSTEM EVALUATED  
USING DEVICE MEASUREMENT DATA AND SIMULATION [49].

Parameter	HISIM (65nm)	65nm data [49]
<b>VGG16</b>		
Total Crossbar Area	49.9 mm <sup>2</sup>	50.7 mm <sup>2</sup>
Total Energy	6.74 mJ	5.94 mJ
Total ADC Area	261.5 mm <sup>2</sup>	261.5 mm <sup>2</sup>
Total ADC Power	17.43 W	17.43 W
<b>Mobilenet</b>		
Total Crossbar Area	13.4 mm <sup>2</sup>	13.7 mm <sup>2</sup>
Total Energy	1.97 mJ	1.29 mJ
Total ADC Area	56.544 mm <sup>2</sup>	56.54 mm <sup>2</sup>
Total ADC Power	3.77 W	3.78 W

factor due to ADC sharing. The area of the tile is estimated based on the crossbar size and the number of processing elements.

3) *Model Calibration*: The IMC chiplet models are calibrated with realistic designs to reliably predict the physical metrics of individual design components, such as area, latency, and power consumption. These values are then combined into the system performance model. Initially, the features of RRAM devices and ADCs are extracted from measurement data at 65nm [49], and then scaled down to 28nm, following a scaling factor of 4.12 for area and 3.37 for power as obtained from [50]. HISIM offers a discrete number of crossbar sizes for users to select, such as 64 × 64, 128 × 128, 256 × 256, and 512 × 512. Other peripherals of the crossbar, such as multiplexers and decoders, are synthesized, similar to those used in [51]. At the PE and tile levels, data bus, NoC, buffers, etc., are included, following those in SIAM [5].

Figure 5 assesses the computing latency modeled by HISIM using measurement data from [49] for an RRAM-based IMC design. Two DNN algorithms, VGG16 [52] and MobileNet [53], are used for evaluation. The inputs to HISIM, including mapping dependency, the number of ADCs per layer, and ADC sharing, are configured the same as those in [49]. For example, the filter in a convolution layer is flattened into

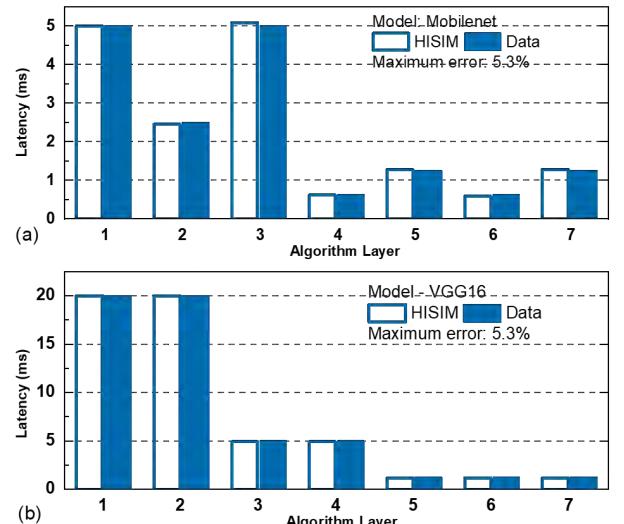


Fig. 5. Computing latency comparison of first seven layers of two DNNs, Mobilenet (a) and VGG16 (b), with 65nm measurement data in [49].

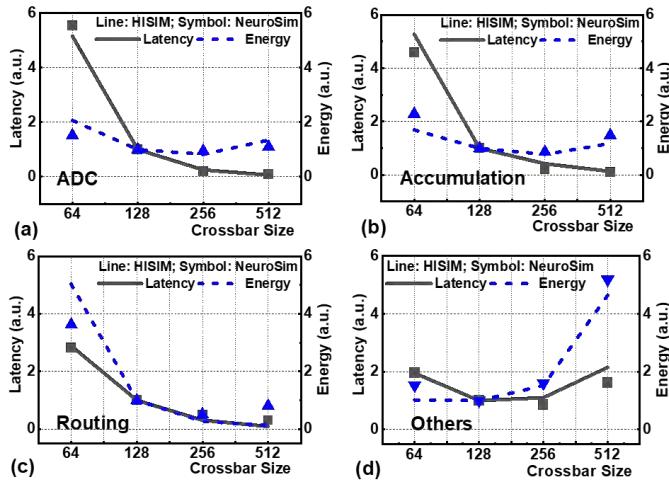


Fig. 6. Comparison of normalized latency and energy with NeuroSim for ResNet110 at 32nm.

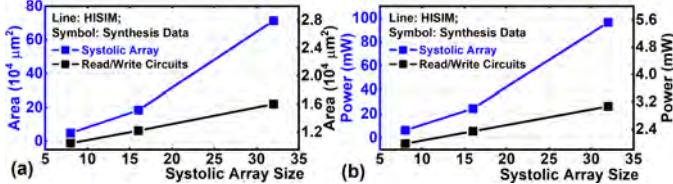


Fig. 7. Comparison of area and power for array and read/write circuits with different systolic array sizes under 28nm.

a 1D vector and mapped onto a column. If the vector does not fit into a single crossbar, it is distributed across multiple crossbars. Additionally, if the number of crossbars required for the layer exceeds the capacity of a single processing element (PE), the layer is mapped onto multiple PEs.

The maximum latency of crossbars mapped to the first layer of VGG16 is first calibrated to that of the reference data. The results are then used to predict the performance of the first seven layers of VGG16 and MobileNet, as presented in Figure 5, with the maximum error at 5.3%. Table III verifies the total area and energy consumption of both algorithms. The energy values in Table III account for both network energy and computing energy. However, the network configuration in HISIM differs from that in [49], resulting in variations in energy comparison. Furthermore, we evaluate the scalability of HISIM models with design variables, such as crossbar size. In this study, we utilize simulations with NeuroSim to validate the nonlinear dependency of peripheral circuits, such as ADC, accumulation, routing, and other peripherals. Figure 6 summarizes the normalized results. At the crossbar level, our system-level models exhibit comparable scalability with NeuroSim in RRAM-based IMC design.

4) *Systolic Array & Other Computing Units:* Currently, HISIM supports the systolic array which is calibrated with Scale-Sim [54] and 28nm synthesis which is shown in Figure 7. In addition, we are expanding HISIM towards other types of computing cores, such as digital IMCs and CPUs, to enable more heterogeneous computing. For digital IMCs, we will synthesize the design and extract performance models, which include the array structure and local buffers for storing and loading partial results. We will incorporate the average time consumed in each stage of the pipeline in the CPU

model, including fetch, decode, execute, and writeback. We will calibrate the model with silicon data, such as that from RISC-V cores. Furthermore, we plan to open the HISIM platform, allowing other researchers to add their own chiplet models for system exploration.

### C. Heterogeneous Interconnection

In AI computing, data movement plays a crucial role in the overall performance of the system. Emerging 2.5D/3D interconnection technologies, with their scaling trend in Figure 2, promise high bandwidth, high connection density, and low energy consumption per bit. The interconnection engine in HISIM integrates compact models that calculate electrical parasitics for various types of interconnections.

1) *2.5D/3D Interconnection:* Figure 8 presents our modeling process, from various interconnect technologies to their geometry definition and the extraction of electrical parasitics. The parasitics are transferred to the network engine for latency and power analysis. Table IV lists the key dimensions of the metal wire for monolithic, 2.5D, and 3D interconnections. The parameters  $l_{\text{wire}}$ ,  $w_{\text{wire}}$ ,  $t_{\text{wire}}$ , and  $p_{\text{wire}}$  define the geometry of interconnections. They are key to parasitic modeling. For 3D interconnection, many technologies, like  $\mu$ bump, hybrid bonding, and TSVs, enable data communication between tiers vertically. The features of a TSV is defined by  $d_{\text{TSV}}$ ,  $h_{\text{TSV}}$ ,  $p_{\text{TSV}}$  and  $t_{\text{ox\_TSV}}$ , as shown in Figure 8. As TSV technology continues to scale down, its dimensions become increasingly comparable to those of on-chip wires, implying a similar bandwidth and network capacity through the vertical TSVs as with the on-chip network. Potential users can adjust the dimensions of the interconnects in HISIM according to their specific technology.

2) *Parasitic Modeling:* For wires in 2D and 2.5D technologies (such as the silicon bridge), we follow the models in the Predictive Technology Model [55] and the roadmap in [27] to

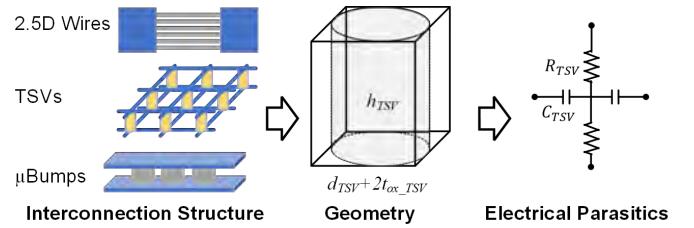


Fig. 8. The workflow of parasitic extraction, including 2D wires, 2.5D wires, 3D TSVs,  $\mu$ Bumps, etc.

TABLE IV  
MODEL PARAMETERS OF 2D/2.5D/3D INTERCONNECTIONS.

Structure	Interconnect	Parameter	Description
2D/2.5D	Wire	$l_{\text{wire}}$	Wire length
		$w_{\text{wire}}$	Wire width
		$t_{\text{wire}}$	Wire thickness
		$p_{\text{wire}}$	Wire pitch
3D	TSV	$d_{\text{TSV}}$	TSV diameter
		$h_{\text{TSV}}$	TSV height
		$p_{\text{TSV}}$	TSV pitch
		$t_{\text{ox\_TSV}}$	Insulation thickness

TABLE V  
SCALING OF TSV PARASITICS IN SIX GENERATIONS.

$r_{TSV}$ ( $\mu m$ )	$d_{TSV}$ ( $\mu m$ )	$h_{TSV}$ ( $\mu m$ )	$R_{TSV}$ ( $m\Omega$ )	$C_{TSV}$ (fF)	$RC$ (fs)
20	40	400	5.45	888.76	4.843
15	30	300	7.26	502.04	3.645
10	20	200	10.89	225.00	2.450
<b>5</b>	<b>10</b>	<b>100</b>	<b>21.78</b>	<b>57.64</b>	<b>1.255</b>
2.5	5	50	43.56	15.09	0.657
1.25	2.5	25	87.12	4.10	0.357

calculate their RC parameters. For a TSV link, we assume the TSV is driven by the driver and followed by the receiver. The TSV is then modeled as the resistor ( $R_{TSV}$ ) and capacitor ( $C_{TSV}$ ) between the driver and the receiver. We adopt the models in [56] to construct the unit cell, as illustrated in Figure 8.  $R_{TSV}$  and  $C_{TSV}$  are formulated as:

$$R_{TSV} = \frac{1}{2} \frac{h_{TSV}}{\sigma_{TSV} \pi (d_{TSV}/2)^2} \quad (8)$$

$$C_{TSV} = \frac{1}{2} \frac{\pi \varepsilon_{ox} h_{TSV}}{\ln\left(\frac{d_{TSV}/2 + t_{ox,TSV}}{d_{TSV}/2}\right)} \quad (9)$$

These parasitic models are usually derived from the distribution of the electric field, and validated by finite-element solvers.

3) *Interconnect Scaling*: HISIM covers multiple generations of interconnect dimensions to facilitate early design exploration. For example, Table V illustrates the TSV roadmap, including the dimensions and RC parasitics [56]. As the size of TSVs continues scaling down, their RC product decreases by more than 10 $\times$  over these six generations, significantly improving data bandwidth. In addition, the reduction in  $C_{TSV}$  contributes to lower energy consumption in data movement. In this paper, we choose the generation with 5 $\mu m$  TSV radius for simulation analysis.

Currently, HISIM only addresses RC parasitic. Users can also substitute the HISIM RC model with their own parasitic models for simulation. We also plan to extend the modeling effort to inductance and other components to support signal integrity analysis at higher frequencies.

#### D. Network Communication

For AI acceleration, efficient data communication is critical for the overall system performance. With large volumes of input and output activations being transferred between adjacent algorithm layers, a high-bandwidth, flexible network is required to connect multiple PEs, tiles, and chiplets. This can be a network-on-chip for a 2D monolithic chip or a network-on-package in 2.5D and 3D systems. As the chiplets communicate through the NoP, the network size is directly influenced by the number of chiplets. The size of the AI model's weights and the hardware configuration together determine the NoP size which influences the performance of the network. A 2D NoC or a 3D NoP consists of multiple channels connected by network routers. Figure 9 presents an example of a 3D network. HISIM models 2D/3D network latency and power consumption in the

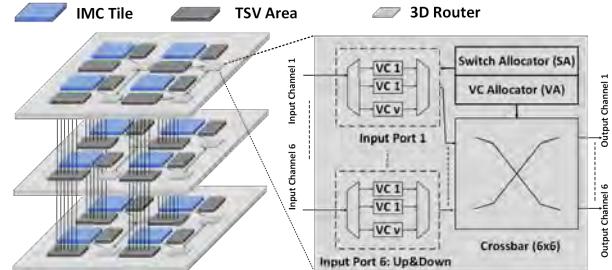


Fig. 9. A 3D network via TSVs and routers.

TABLE VI  
INPUT PARAMETERS OF NETWORK MODELS.

Inputs	Description
<b>VC router</b>	
$t_{RC}$	Delay in routing computation
$t_{VA}$	Delay in virtual channel allocation delay
$t_{SA}$	Delay in switch allocation
$t_{ST}$	Delay in switch traversal
$t_L$	Delay in channel traversal
$t_{enq}$	Queuing delay
<b>Channel</b>	
$Q_{2d}, Q_{3d}$	Data volume for 2D/3D routing
$W_{2d}, W_{3d}$	2D/3D channel width
<b>Network</b>	
$H_{2d}, H_{3d}$	2D/3D hop count

network engine for various network topologies. In addition, HISIM covers the IO protocol in 2.5D silicon bridges for chiplet integration.

1) *2D/3D Network Modeling*: Cycle-accurate simulators are available for the 2D NoC latency and throughput evaluations, such as Booksim [34]. BookSim traces the data flow through each module. Such a cycle-accurate process requires running simulations with each input data point, leading to a long simulation time. To speed up the simulation while maintaining the accuracy in latency prediction, we generalize BookSim to both 2D and 3D networks and formulate an analytical model for network latency based on equations in [57]:

$$L_{NoC} = (H_{2d} + H_{3d}) \times t_{router} + t_{enq} \times \frac{Q_{2d}}{W_{2d}} + t_{enq} \times \frac{Q_{3d}}{W_{3d}} \quad (10)$$

$$t_{router} = t_{RC} + t_{VA} + t_{SA} + t_{ST} + t_L \quad (11)$$

where  $H_{2d}, H_{3d}$  are the hop count from the NoC network for 2D and 3D, respectively.  $t_{router}$  is the latency associated with the routing computation, switch allocation, etc., as explained in Table VI. This equation represents the contention-free message latency for the 3D virtual channel router, as shown in Figure 9.

We validate the latency equations with BookSim, as shown in Figure 10. The network trace files are derived from VGG-16 on ImageNet, mapped to 2.5D/3D integration. The prediction from our analytical equation accurately follows the cycle-accurate results from BookSim. As shown in Figure 9, mapping an entire AI algorithm to a 3D stack involves both 2D NoCs (within-tier or on-chip) and 3D NoPs (cross-tier). To calculate the total hops, we sum the  $H_{2d}$  and  $H_{3d}$  using Algorithm 1. Our analytical model significantly accelerates

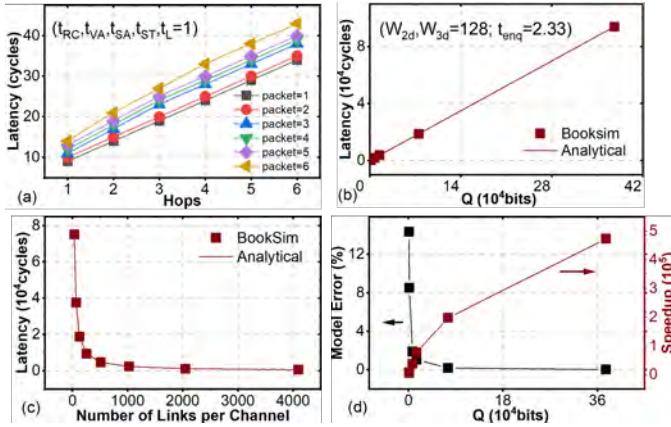


Fig. 10. Calibration of analytical network with cycle-based BookSim simulations: (a) Latency with different sizes of packets; (b) Latency with different data volumes; (c) Latency with various channel bandwidths, represented as the number of links per channel; and (d) Trade-off between model errors and speedup of calculation.

**Algorithm 1** Counting 2D/3D hops and data bits for the entire AI model

**Input:** Number of tiles for each layer ( $T$ ), Number of input activations for each layer ( $A$ ), Number of AI model layers ( $L$ )

**Output:**  $H_{2d}$ ,  $H_{3d}$ ,  $Q_{2d}$ , and  $Q_{3d}$ ;

**for**  $l=1:L$  **do**

    Based on the placement method, decide the location of each tile in the 3D system ( $x_l, y_l, z_l$ )

    Divide activations  $A$  into  $A_{2d}$ ,  $A_{3d}$

$Q_{2d}+=A_{2d}$ ;  $Q_{3d}+=A_{3d}$

**for**  $t=1:T$  **do**

        Find the position for the source tile in this layer

        Find the position of the destination tile in next layer

$2d_{hop}=|x_l-x_{l+1}|+|y_l-y_{l+1}|$ ;  $3d_{hop}=|z_l-z_{l+1}|$

**end**

$H_{2d}+=2d_{hop}$ ;  $H_{3d}+=3d_{hop}$

**end**

latency calculations and achieves high accuracy across typical data volumes.

We adopt the analytical models from Orion 2.0 [58] to assess the power consumption and area of 2D/3D networks:

$$P_{NoC} = P_{2d} + P_{3d} \quad (12)$$

$$P_{2d} = (E_{2d_{cl}} + E_{2d_r})/L_{2d_{NoC}}; P_{3d} = (E_{3d_{cl}} + E_{3d_r})/L_{3d_{NoC}} \quad (13)$$

where  $P_{NoC}$  is the total power consumption of the network, including 2D NoCs (within-tier or on-chip) and 3D NoPs (cross-tier). The power consumption in 2D/3D networks relies on energy consumption and associated latency of each component.  $E_{2d_{cl}}$ ,  $E_{3d_{cl}}$  represents the energy consumption of 2D/3D channels, and  $E_{2d_r}$ ,  $E_{3d_r}$  represents the energy consumption of 2D/3D routers. The overall power consumption of the 3D network is based on the power consumption of the channels and routers, as well as the ratio of their active time in  $L_{NoC}$ . Moreover, the dynamic power of both channels and routers depends on the generation of interconnection technologies, as presented in the previous section.

**2) 2.5D AIB Interface:** To enable inter-chiplet communication within the 2.5D package, a dedicated signaling interface is necessary to maintain signal integrity. These interfaces, such as Advanced Interface Bus (AIB) [40] or Universal chiplet interconnect express (UCIE) [41], are usually standardized by the design industry. Figure 11 illustrates the AIB 2.0 interface that is modeled in HISIM. Each chiplet can accommodate up to four columns of AIB, each supporting multiples of 4 channels and up to a maximum of 24 channels. Each AIB channel features a balanced transceiver (Tx)-receiver (Rx) configuration and can handle data widths ranging from 20 to 80 for each Tx and Rx channel. Furthermore, each channel is equipped with a Tx and Rx adapter and IO modules. The number of IO ports in a channel is determined by various factors, including the number of AIB Tx/Rx lines and essential IO signals such as clock, control, and sideband signals. Additionally, the adapter incorporates a Tx and Rx FIFO, each of which can be configured to operate at full, half, or quarter rates by adjusting the clock frequencies.

To assess the power and performance of the AIB 2.0 interface, we construct an analytical model based on input parameters detailed in Table VII. This model is summarized as follows:

$$\text{Latency: } L_{Tx} = L_{FF_{wr\_clk}} + L_{FIFO} + L_{FF_{fwd\_clk}} + L_{IO} \quad (14)$$

$$\text{Latency: } L_{Rx} = L_{IO} + L_{FIFO} + 2L_{FF_{rd\_clk}} \quad (15)$$

$$\text{Dynamic Power: } P_{AIB} = (P_{clocks} + P_{data})n_{ch} \quad (16)$$

Here, the dynamic power due to clock switching and data switching is further decomposed as:

$$P_{clocks} = P_{fs\_fwd\_clk} + P_{ns\_fwd\_clk} + P_{rd\_clk} + P_{wr\_clk} \quad (17)$$

$$P_{data} = P_{Txdata} + P_{Rxdata} \quad (18)$$

The dynamic power arising from each clock-switching event of a single AIB channel is estimated based on several factors, including the number of Tx/Rx data lines ( $n_{tx/rx}$ ), voltage, specific clock frequency, and the fraction of duration for which the AIB is switched on ( $\alpha_{aib}$ ), representing the activity factor.

$$P_{clock_i} = (\gamma_{1i}n_{tx/rx} + \gamma_{2i})V^2\alpha_{aib}f_{clk_i} \quad (19)$$

where  $\gamma_{1i}$  and  $\gamma_{2i}$  are calibrated using RTL synthesis at 28nm of open-source AIB codes [59]. Similarly, the dynamic power originating from data switching for a single AIB single channel is assessed, depending on the input switching frequency ( $f_{in_i}$ ) and an input switching activity factor that is a function of input sparsity ( $S_{in_i}$ ).

The area of the AIB interface circuitry is estimated, assuming uniform dimensions for each component, with all IO

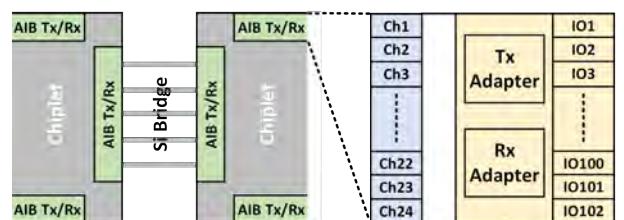


Fig. 11. The architecture of the 2.5D interface, such as AIB, includes Tx/Rx adapters, silicon bridge, etc.

cells aligned along the same edge as the  $\mu$ bump orientation, as specified in [40].

$$\text{Area: } A_{AIB} = (Len_{IOch}(W_{IO} + W_{Adpt}))n_{ch} \quad (20)$$

Here,  $Len_{IOch}$  represents the length of the stack of IO cells in a single column, while  $W_{IO}$  and  $W_{Adpt}$  denote the width of an IO cell and an adapter, respectively.

$$Len_{IOch} = n_{IO} \sqrt{A_{IO}}, W_{IO} = \sqrt{A_{IO}} \quad (21)$$

$$W_{Adpt} = \sqrt{A_{TxAdpt} + A_{RxAdpt} + A_{Other}} \quad (22)$$

where the area of the Tx and Rx adapter relies on the number of Tx/Rx lines:

$$A_{TxAdpt} = \delta_1 n_{Tx} + \delta_2, A_{RxAdpt} = \delta_3 n_{Rx} + \delta_4 \quad (23)$$

In this context,  $A_{IO}$  denotes the area of a single IO cell. The area of the  $\mu$ bump array is also estimated, depending on the number of IO signals, channels, number of IOs per column, and row and column pitches:

$$A_{\mu bump} = n_{ch} n_{IOcl} p_{cl} \frac{p_{rw}}{2} \text{ceil}\left(\frac{n_{IO}}{n_{IOcl}}\right) \quad (24)$$

Different values are provided for low, medium and high-density  $\mu$ bump arrays [40].

All AIB equations within HISIM are calibrated with RTL synthesis at 28nm [59] to extract latency, area, and power parameters. Table VIII evaluates HISIM results with silicon data [60]. The latency and power models within HISIM are developed under a Double Data Rate (DDR) configuration across three distinct modes of operation: full, half, and quarter rate. The selection of these three modes directly dictates the aggregated data width of the Tx/Rx module [40]. Note that the FIFO within the AIB adapter operates asynchronously. HISIM adopts the worst-case latency over the temporal span of the data stream.

Besides the AIB interface, HISIM further incorporates analytical performance models for the silicon bridge between chiplets, as shown in Figure 11. The area of the silicon bridge

TABLE VII  
INPUT PARAMETERS OF THE AIB MODEL.

Inputs	Description
<b>Clock</b>	
$ns\_fwd\_clk$	Near side clock of Tx IO module
$fs\_fwd\_clk$	Far side clock of Rx IO module
$rd\_clk$	Read clock of Tx FIFO
$wr\_clk$	Write clock of Tx FIFO
<b>Interface</b>	
$n_{ch}$	Number of AIB Channels
$n_{IO}$	Number of IO ports per channel
$n_{Rx}$	Number of Rx lines per channel
$n_{Tx}$	Number of Tx lines per channel
<b><math>\mu</math>bump</b>	
$n_{IOcl}$	Number of AIB IOs per $\mu$ bump column
$p_{rw}$	Aligned-row bump-to-bump pitch
$p_{col}$	Aligned-column bump-to-bump pitch
<b>Silicon bridge</b>	
$W_{wire}$	Width of 2.5D wires
$L_{wire}$	Length of 2.5D wires

TABLE VIII  
COMPARISON WITH SILICON DATA AT 40 TX AND 40 RX PINS.

Parameter	HISIM	Data [60]
<b>AIB Configuration</b>		
Technology Node	28nm	22nm
Aligned-row bump-to-bump pitch	36 $\mu$ m	36 $\mu$ m
AIB Data rate (Gbps/pin)	4	4
Number of AIB Channels ( $n_{ch}$ )	24	24
Number of AIB IO ports ( $n_{IO}$ )	102	102
Total AIB Bandwidth (Tbps)	7.68	7.68
<b>Area Efficiency</b>		
Total AIB Area (mm <sup>2</sup> )	5.7	4.5
Bandwidth Density (Tbps/mm <sup>2</sup> )	1.35	1.705
IO Buffer Size( $\mu$ m <sup>2</sup> /pin)	100	91.2
<b>Energy Efficiency</b>		
IO Latency (ns)	1.45	1.5
Adapter Energy (pJ/b)	0.29	0.32

is a function of the parameters in Table VII, and is estimated under the layout configuration in [61]:

$$A_{wire} = \left(\frac{p_{rw}}{2n_{IOcl}} n_{IO} + W_{wire}\right) L_{wire} n_{ch} \quad (25)$$

With  $RC$  parasitics calculated by the interconnect engine, the latency of the bridge is calculated using the Elmore delay model. The dynamic power depends on the frequency of all signals transmitted between AIB interfaces:

$$P_{wire} = \sum_i \alpha_i f_i \sum_j C_j V^2 n_{ch} \quad \forall i \in [1, n_{IO}] \quad (26)$$

where  $\alpha_i$  represents the activity factor of signal  $i$ , and  $f_i$  denotes the frequency of switching for signal  $i$ .

3) *Other Chiplet Interfaces*: While AIB is currently available, we plan to integrate additional types of 2.5D/3D interfaces into HISIM. Examples are PCIe, DDR, and HBM, which will further address data communication between computing chiplets and external memory. Furthermore, we will continually update the HISIM models to accommodate various generations of  $\mu$ bumps, TSVs, and wire lengths and pitches. These improvements will enable a more comprehensive and accurate representation of future packaging systems and their performance characteristics.

### E. Thermal Analysis

Thermal analysis is critical to heterogeneous integration, especially in 3D stacking scenarios. The stacking of multiple tiers inevitably reduces the capability of heat dissipation and raises the temperature. As a consequence, degrading the electromechanical reliability of an HI system. Using power consumption data and chip area, we build up the thermal resistance model to generate the temperature map for a 2.5D/3D system. Our thermal models offer a user-friendly interface that allows the integration with other simulators, enabling them to incorporate power and area results for comprehensive thermal analysis.

1) *Inputs to Thermal Analysis*: Figure 12 presents the process in HISIM. The thermal analysis engine requires the following inputs to accurately predict temperatures.

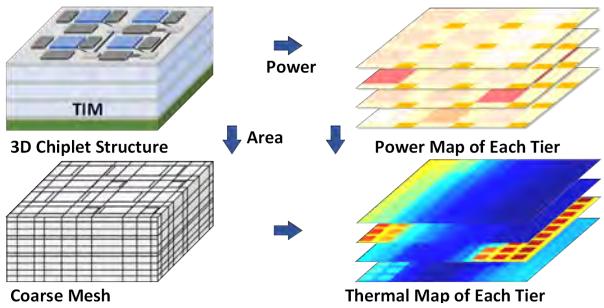


Fig. 12. Thermal prediction for a 2.5D/3D system: HISIM first generates the power and area maps for each component, based on the algorithm workload and the system structure; the thermal engine then computes the temperature map using a coarse mesh.

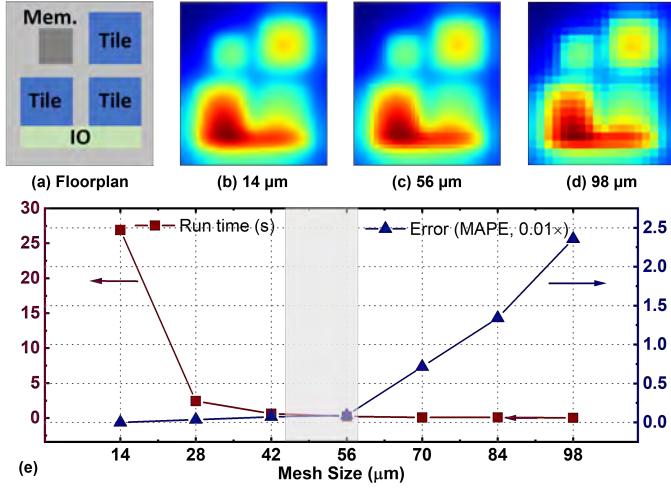


Fig. 13. (a) The structure of a chiplet, at  $3 \times 3 \text{ mm}^2$ ; (b-d) Temperature maps at different mesh sizes; (e) Trade-off between simulation time and MAPEs.

**Geometry and material information** includes information about the structure (e.g., dimensions and placement) and materials (e.g., the thermal conductivity of the chiplet and thermal interface materials) that constitute the chiplet system.

**Power map** includes the power profile of computing units and networks that contribute to heat generation.

**Granularity** defines the resolution of the mesh used for partitioning the system. A smaller mesh size improves accuracy but compromises simulation speed.

**Boundary conditions** include the ambient temperature, usually set at  $298K$ , and additional heat dissipation elements like the heat sink, substrate, and the surrounding air layer.

2) *Finite Element Method*: Mathematically, the first two inputs described above are represented by two 3D arrays:  $\mathbf{K}$  and  $\mathbf{P}$ , corresponding to the conductivity map and power map, respectively. Each entry within the array corresponds to a voxel, which serves as the smallest unit for thermal analysis. The physical size represented by the voxel is determined by the

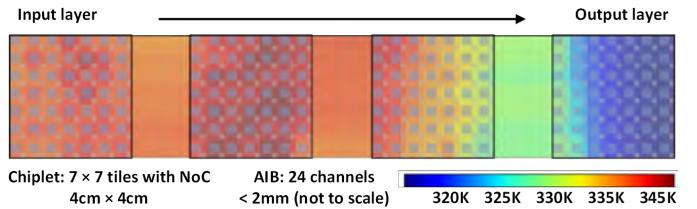


Fig. 14. A 2.5D system for DenseNet-121. Each chiplet consists of  $7 \times 7$  computing tiles and NoC routers, at an area of  $4 \times 4 \text{ cm}^2$ . They are connected by AIB. The thermal simulation uses a mesh size of  $60 \mu\text{m}$ .

granularity  $c_l, c_w, c_h$  which are for length, width, and height, respectively. To conduct the thermal analysis, we use the nodal analysis  $\mathbf{GT} = \mathbf{P}$  to predict the static thermal map  $\mathbf{T}$ , given the flattened power map  $\mathbf{P}$  and the conductance matrix  $\mathbf{G}$  [67]. The conductance  $g_{ij}$  between two physically connected voxels  $v_i, v_j$  is evaluated by

$$g_{ij} = -A_{ij}/(l_i/k_i + l_j/k_j) \quad (27)$$

where  $A_{ij}$  is the contact area,  $l_i, l_j$  are the distances from the center of each voxel to the contacted region, and  $k_i, k_j$  are the corresponding conductivities. The diagonal of  $\mathbf{G}$  is evaluated by  $g_{ii} = -\sum_j g_{ij}$ . After building up the model, we collect data points from publications and calibrate the thermal properties of different materials in the model. Table IX summarizes the calibration.

In simulations with the finite-element method (FEM), the selection of granularity (i.e., mesh size) is essential to both accuracy and simulation efficiency. To illustrate that, we simulate a chiplet consisting of three computing tiles, one SRAM, and one AIB. The total chiplet area is  $3\text{mm} \times 3\text{mm}$ . The system also has a heat sink on the top, a packaging substrate, and an air boundary layer. Figure 13 presents the trade-off between simulation time and accuracy, with results from a fine mesh size, such as  $14\mu\text{m}$ , as the baseline. As shown in the figure, a mesh size of  $50 - 60\mu\text{m}$  is found to be optimal for this chiplet configuration before the mean absolute percentage error (MAPE) starts increasing. This value aligns with the results in [68]. A second example is presented in Figure 14. It demonstrates a 2.5D system with four IMC chiplets for end-to-end computation of DenseNet-121. Although both computation and data volume are higher in the middle layers, the workload decreases towards the final output, leading to a cooler temperature.

3) *Machine Learning Method*: Despite using a coarse mesh, numerical simulations with FEM still consumes considerable time. To speed up thermal analysis for design space exploration, our ongoing research focuses on machine learning techniques. Based on the same mesh size that is consistent with FEM, we propose to develop a graph neural network (GNN) to simulate the heat exchange within a chiplet system. The training of GNN is assisted by FEM results. The inference of GNN involves the operations of aggregation and transformation, which are confined to each node. Therefore, the computation scale of GNN is much smaller compared to FEM, which operates on a full 3D matrix. This advantage promises a significant acceleration in temperature prediction. Such a

TABLE IX  
CALIBRATION OF HISIM WITH PUBLISHED 3D SYSTEMS.

Die Size ( $\text{mm}^2$ )	Tier Count	Power Density ( $\text{mW/mm}^2$ )	Peak Temp. (°C)	HISIM (°C)
100 [62]	2	2.85	27	26.78
36 [63]	3	27.78	68.6	69.25
9 [64]	3	38.99	47	41.09
49 [65]	4	40.81	53.85	56.18
22 [66]	1	140	53	43.38

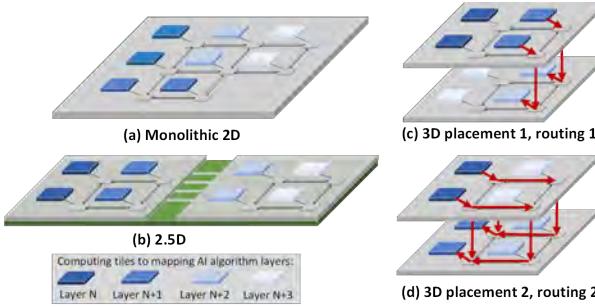


Fig. 15. Placement and routing for 2D/2.5D/3D systems. The 3D system offers more options due to the vertical link.

thermal model has been developed, submitted for publication, and will be integrated into HISIM in the future.

#### IV. DESIGN EVALUATION WITH HISIM

The primary objective of HISIM is to provide an end-to-end simulator for chiplet-based heterogeneous integration (HI). This simulator needs to be comprehensive to cover a wide range of chiplet architectures and interconnection technologies, ranging from monolithic to 2.5D and 3D structures. By varying the type of computing units and network topologies, users are able to conveniently simulate and explore the design space for further optimization.

##### A. Experimental Setup

In our experiments, we simulate a set of representative AI models with HISIM, including ResNet-110 (1.7M parameters) on CIFAR-100, DenseNet-121 (7.05M parameters) on ImageNet, a 2-layer graph convolutional network (GCN) on Cora, and a vision transformer (ViT, 86M parameters) on ImageNet. We quantize the weights and activations of AI models to 8-bit. All experiments were performed on the Intel Xeon CPU platform. We use the RRAM-based in-memory computing chiplet for the computing core, as specified in Section III-B1. The default technology node is 32nm/28nm CMOS. We follow the method in Section III-B1 for the partition of algorithms on the IMC crossbar array, assuming stationary weight mapping to the crossbars. Both computing units and networks operate at a default frequency of 1GHz. For the 3D chiplet-based architecture, we follow that in [21] to construct the stack. We adopt the Face-to-Back configuration to build up the 3D multi-chiplet systems with TSVs. The maximum number of tiers is four in this study. The 3D network routers in each tier support data communication both within the chiplet as well as vertically to other chiplets via TSVs. The default configuration includes three virtual channels with a buffer size of 10 per virtual channel. The packet size is 1 and the flit size depends on the channel width. The TSV array consists of 70% signal TSVs and 30% power/ground TSVs [21]. The default diameter for each TSV is  $10\mu\text{m}$ , as highlighted in Table V.

##### B. Placement and Routing

After partitioning the weights of an AI model into the IMC tiles, the placement and routing of these tiles into a 2.5D/3D architecture further determine the overall system performance. Figure 15 illustrates the scenarios. For a 2D chip or 2.5D

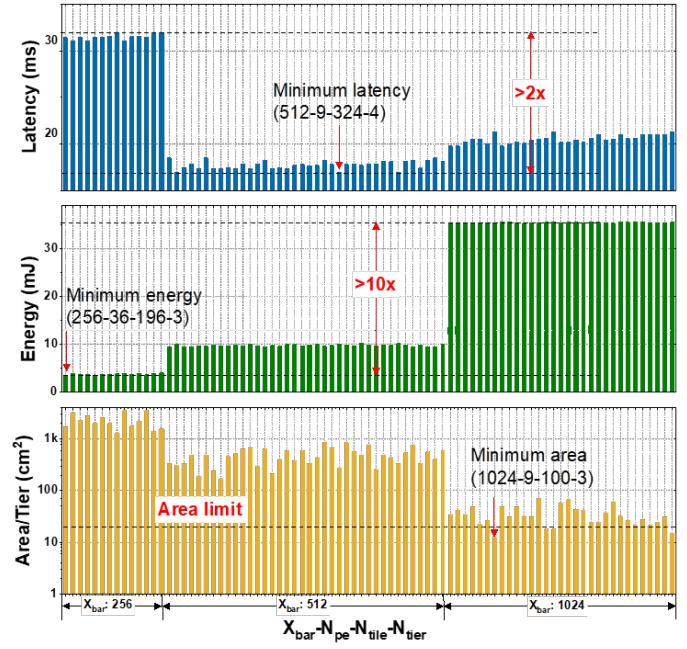


Fig. 16. Design space exploration of ViT on a 3D system. Design configurations include  $X_{bar}(256,512,1024)$ ,  $N_{pe}(9,16,25,36)$ ,  $N_{tile}(49,64,...,361,400)$ , and  $N_{tier}(1,2,3,4)$ .

chiplet system (Figure 15(a) and Figure 15(b)), HISIM follows the sequence of AI algorithm layers to place and route the tiles, in order to minimize the hops of data movement. Figure 14 uses this method to demonstrate DenseNet-121.

In a 3D system, there are more options because the bandwidth of the vertical link is comparable to that of the links within the tier. As an example, Figure 15(c) and Figure 15(d) present two different placement methods, assuming there are four algorithm layers, with each layer taking two tiles. In the first method (Figure 15(c)), tiles from adjacent layers are placed on the same tier until the tier is full. Then, the tiles from the next layer are placed on another tier. In the second method (Figure 15(d)), tiles from adjacent layers are placed vertically across different tiers and then expand to other areas within the tier. This results in more data communication occurring in the vertical direction compared to the first method. Furthermore, the number of hops within the tier can be adjusted, influencing the number of vertical TSVs that are accessible. Depending on the data volume and sequence of a specific AI algorithm, the preferred placement and routing methods vary to minimize overall latency [69]. In HISIM, users can customize the placement and routing methods to explore the 3D network.

##### C. Design Exploration for AI Computing

Using the full set of HISIM, we demonstrate end-to-end design exploration of multiple AI algorithms in this section.

1) *Speedup in Simulation*: We demonstrate HISIM with ResNet-110 on CIFAR-100, DenseNet-121 on ImageNet, GCN on Cora, and ViT on ImageNet. These algorithms are mapped onto a 3D system with various number of tiers. The simulation speed is compared to the combined results of the state-of-the-art IMC simulator [32] and the network simulator [34]. Table X summarizes the end-to-end latency and energy con-

TABLE X  
END-TO-END SIMULATION OF REPRESENTATIVE AI ALGORITHMS ON 3D HISIM.

AI Model	$X_{bar}$	$N_{tier}$	Latency (ms)		Energy (mJ)		Area/Tier ( $cm^2$ )	Simulation Time (ms)		Speedup
			Tile	Network	Tile	Network		HISIM	[32] + [34]	
ResNet-110	256	4	4.80	0.52	0.074	0.013	2.10	18.50	$4.25 \times 10^5$	$2.3 \times 10^4$
DenseNet-121	1024	4	20.66	7.19	39.15	0.59	15.50	81.00	$8.10 \times 10^6$	$1.0 \times 10^5$
GCN	1024	2	164.40	425.55	834.60	6.48	117.84	29.70	$5.30 \times 10^7$	$1.78 \times 10^6$
ViT	1024	3	12.15	0.55	35.25	0.27	12.81	73.56	$3.16 \times 10^6$	$4.33 \times 10^4$

sumption, as well as the breakdown to computing tiles and networks. Depending on the algorithm structures, data movement can dominate the overall latency, as observed in the case of GCN. Computing tiles are usually the primary contributors to energy consumption. Compared to conventional simulators, HISIM is  $10^4 - 10^6 \times$  faster in performance prediction, as shown in Table X. Such acceleration confirms the advantage of analytical performance models.

2) *Design Space Exploration:* For a particular AI algorithm, optimizing the hardware configuration is challenging due to the vast space of design parameters and multiple constraints involved. Therefore, the efficiency of the performance simulator is critical for quickly searching the design space and guiding the user toward an optimal solution. Using the ViT algorithm as the benchmark, Figure 16 demonstrates the process and highlights its importance. Design variables include the crossbar size ( $X_{bar}$ ), the number of PEs per tile ( $N_{pe}$ ), the number of tiles per tier ( $N_{tile}$ ), and the number of 3D tiers ( $N_{tier}$ ). In total, there are 672 design configurations. HISIM predicts the end-to-end latency, energy, and area per tier for all of them within 48.8 seconds. As observed in Figure 16, there are dramatic differences in power, performance, and area (PPA) across various configurations. Throughout the range of 672 design configurations tested in this experiment, we observe that energy consumption differs by more than  $10 \times$ , while latency varies by more than  $2 \times$ . The specific configurations optimized for low power or high speed also differ significantly. Some configurations may not be practical for hosting the ViT model due to the area constraint of a monolithic chiplet. Therefore, it is critical to conduct design space exploration at an early stage for guiding further design optimization within a viable range of configurations.

A second example is presented in Figure 17. In this study, we map the DenseNet-121 model to 2D (one monolithic chip), 2.5D (multiple chiplets), and 3D (multiple tiers). With stationary weights applied to the IMC design, the total number of computing tiles remains constant across all configurations. The crossbar size is 1024. Transitioning from 2D to 2.5D slightly reduces overall latency and energy consumption. However, the peak temperature increases due to the introduction of the AIB interface. When moving to 3D configurations, there is a significant reduction in latency, highlighting the advantages of 3D TSVs in terms of bandwidth. Nevertheless, the peak temperature rises due to increased power density in the 3D stack. For both examples, early-stage design exploration is essential to identifying the most feasible configurations, balancing the trade-offs between PPAs, and improving the efficiency.

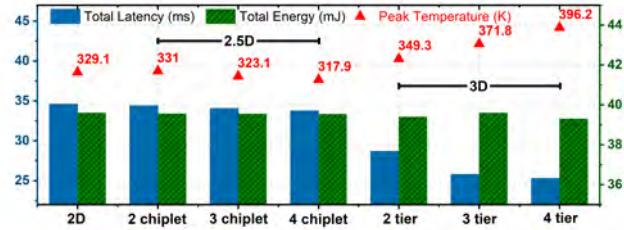


Fig. 17. Comparison of 2D, 2.5D and 3D mapping of DenseNet-121, at a constant number of IMC tiles.

## V. CONCLUSION

In this work, we propose a new benchmark tool, Heterogeneous Integration Simulator with Interconnect Modeling (HISIM), for early-stage design exploration of 2.5D/3D systems. HISIM develops a set of analytical performance models for various computing cores, interconnection technologies, and network topologies. It provides fast and accurate electro-thermal analysis, scalable with different design configurations. Compared to conventional benchmark tools, HISIM achieves  $10^4 - 10^6 \times$  speedup in the evaluation of power, performance, and area (PPA), supporting rapid search in the vast design space. The HISIM code is available at <https://github.com/mec-UMN/HISIM>. It will be continuously updated with new models and design configurations. This repository provides access to the tool, allowing researchers and designers to perform efficient and accurate design exploration of 2.5D/3D systems.

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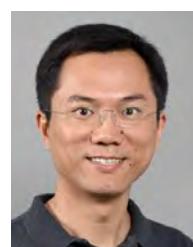
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